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IEC 60068-2-20

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INTERNATIONAL STANDARD

**Environmental testing –
Part 2-20: Tests – Test T: Test methods for solderability and resistance to
soldering heat of devices with leads**

INTERNATIONAL
ELECTROTECHNICAL
COMMISSION

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

ENVIRONMENTAL TESTING –

Part 2-20: Tests – Test T: Test methods for solderability and resistance to soldering heat of devices with leads

FOREWORD

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International Standard IEC 60068-2-20 has been prepared by IEC technical committee 91: Electronics assembly technology.

This fifth edition cancels and replaces the fourth edition, published in 1979 and its Amendment 2 (1987). Amendment 2 includes Amendment 1. This fifth edition constitutes a technical revision and includes test conditions and requirements for use of lead-free solder.

The major technical changes with regard to the fourth edition are the following:

- the solder globule test is deleted;
- test conditions and requirements for lead-free solders are added.

The text of this standard is based on the following documents:

FDIS	Report on voting
91/764/FDIS	91/774/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all the parts in the IEC 60068 series, under the general title *Environmental testing*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

A bilingual version of this publication may be issued at a later date.

ENVIRONMENTAL TESTING –

Part 2-20: Tests – Test T: Test methods for solderability and resistance to soldering heat of devices with leads

1 Scope and object

This part of IEC 60068 outlines Test T, applicable to devices with leads. Soldering tests for surface mounting devices (SMD) are described in IEC 60068-2-58.

This standard provides procedures for determining the solderability and resistance to soldering heat of devices in applications using solder alloys, which are eutectic or near eutectic tin lead (Pb), or lead-free alloys.

The procedures in this standard include the solder bath method and soldering iron method.

The objective of this standard is to ensure that component lead or termination solderability meets the applicable solder joint requirements of IEC 61191-3 and IEC 61191-4. In addition, test methods are provided to ensure that the component body can resist against the heat load to which it is exposed during soldering.

NOTE Information about wetting time and wetting force can be obtained by test methods using a wetting balance. See IEC 60068-2-54 (solder bath method) and IEC 60068-2-69 (solder bath and solder globule method for SMDs).

2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60068-1, *Environmental testing – Part 1: General and guidance*

IEC 60068-2-2, *Environmental testing – Part 2-2: Tests – Tests B: Dry heat*

IEC 60068-2-66, *Environmental testing – Part 2-66: Test methods: Test Cx: Damp heat, steady state (unsaturated pressurized vapour)*

IEC 60068-2-78, *Environmental testing – Part 2-78: Tests – Test Cab: Damp heat, steady State*

IEC 60194, *Printed board design, manufacture and assembly – Terms and definitions*

IEC 61191-3, *Printed board assemblies – Part 3: Sectional specification – Requirements for through-hole mount soldered assemblies*

IEC 61191-4, *Printed board assemblies – Part 4: Sectional specification – Requirements for terminal soldered assemblies*